

AO8820



Common-Drain Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

The AO8820/L uses advanced trench technology to provide excellent $R_{\rm DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V $V_{\rm GS(MAX)}$ rating. It is ESD protected. This device is suitable for use as a uni-directional or bidirectional load switch, facilitated by its common-drain configuration. AO8820 and AO8820L are electrically identical.

- -RoHS Compliant
- -AO8820L is Halogen Free

Features

 $V_{DS}(V) = 20V$

 $I_D = 7A \ (V_{GS} = 10V)$

 $R_{DS(ON)}$ < 21m Ω (V_{GS} = 10V)

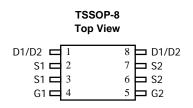
 $R_{DS(ON)}$ < 24m Ω (V_{GS} = 4.5V)

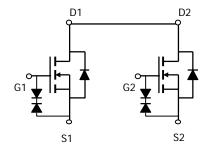
 $R_{DS(ON)}$ < 28m Ω (V_{GS} = 3.6V)

 $R_{DS(ON)}$ < 32m Ω (V_{GS} = 2.5V)

 $R_{DS(ON)}$ <50m Ω (V_{GS} = 1.8V)

ESD Rating: 2000V HBM





Absolute Maximum Ratings T _A =25°C unless otherwise noted								
Parameter		Symbol	Maximum	Units				
Drain-Source Voltage		V_{DS}	20	V				
Gate-Source Voltage		V_{GS}	±12	V				
Continuous Drain	T _A =25°C		7					
Current ^A	T _A =70°C	I_D	5.5	Α				
Pulsed Drain Current ^B		I _{DM}	30					
	T _A =25°C	$-P_{D}$	1.5	W				
Power Dissipation A	T _A =70°C		0.96	T VV				
Junction and Storage Temperature Range		T_J , T_{STG}	-55 to 150	°C				

Thermal Characteristics								
Parameter	Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	Ь	64	83	°C/W			
Maximum Junction-to-Ambient A	Steady-State	teady-State $R_{\theta JA}$		120	°C/W			
Maximum Junction-to-Lead ^C Steady-State		$R_{\theta JL}$	53	70	°C/W			

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units	
STATIC F	PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =16V, V _{GS} =0V			1	μА	
		T _J =55°C			5		
I_{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±10V			10	μA	
BV_{GSO}	Gate-Source Breakdown Voltage	V_{DS} =0V, I_{G} =±250uA	±12			V	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_D=250\mu A$	0.5	0.65	1	V	
I _{D(ON)}	On state drain current	V _{GS} =4.5V, V _{DS} =5V	30			Α	
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =7A		16.5	21		
		T _J =125°C		23.1			
		V _{GS} =4.5V, I _D =6.6A		19	24	mΩ	
		V _{GS} =3.6V, I _D =6A		22	28		
		V _{GS} =2.5V, I _D =5.5A		25	32		
		V _{GS} =1.8V, I _D =2A		35	50		
g _{FS}	Forward Transconductance	V_{DS} =5V, I_{D} =7A		25		S	
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V		0.75	1	V	
Is	Maximum Body-Diode Continuous Current			2.5		Α	
DYNAMIC	PARAMETERS						
C _{iss}	Input Capacitance			615		pF	
C _{oss}	Output Capacitance	V _{GS} =0V, V _{DS} =10V, f=1MHz		150		pF	
C _{rss}	Reverse Transfer Capacitance			120		pF	
R_g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz		1.2		Ω	
SWITCHI	NG PARAMETERS	· ·					
Q_g	Total Gate Charge			8.5	12	nC	
Q_{gs}	Gate Source Charge	V _{GS} =4.5V, V _{DS} =10V, I _D =7A		1.2		nC	
Q_{gd}	Gate Drain Charge	╗		3		nC	
t _{D(on)}	Turn-On DelayTime			7		ns	
t _r	Turn-On Rise Time	V_{GS} =5V, V_{DS} =10V, R_{L} =1.4 Ω ,		13		ns	
$t_{D(off)}$	Turn-Off DelayTime	R_{GEN} =3 Ω		29		ns	
t _f	Turn-Off Fall Time	7		11		ns	
t _{rr}	Body Diode Reverse Recovery Time	I _F =7A, dI/dt=100A/μs		15		ns	
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =7A, dI/dt=100A/μs		5		nC	

A: The value of $R_{\theta,JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t \leq 10s thermal resistance rating.

Rev 3: Feb 2008

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead R $_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using <300 µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

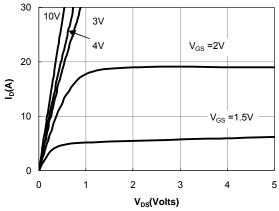


Figure 1: On-Regions CharacteristiCS

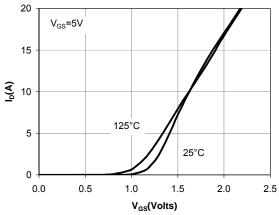


Figure 2: Transfer Characteristics

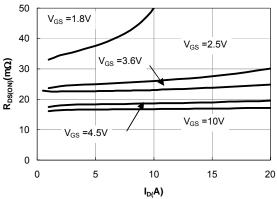


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

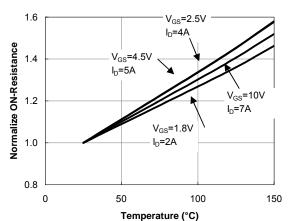


Figure 4: On-Resistance vs. Junction Temperature

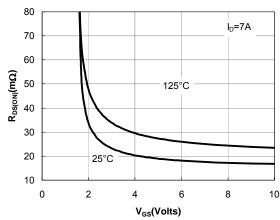


Figure 5: On-Resistance vs. Gate-Source Voltage

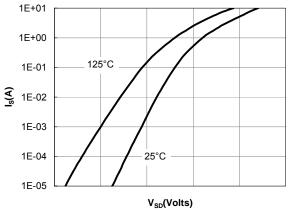


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

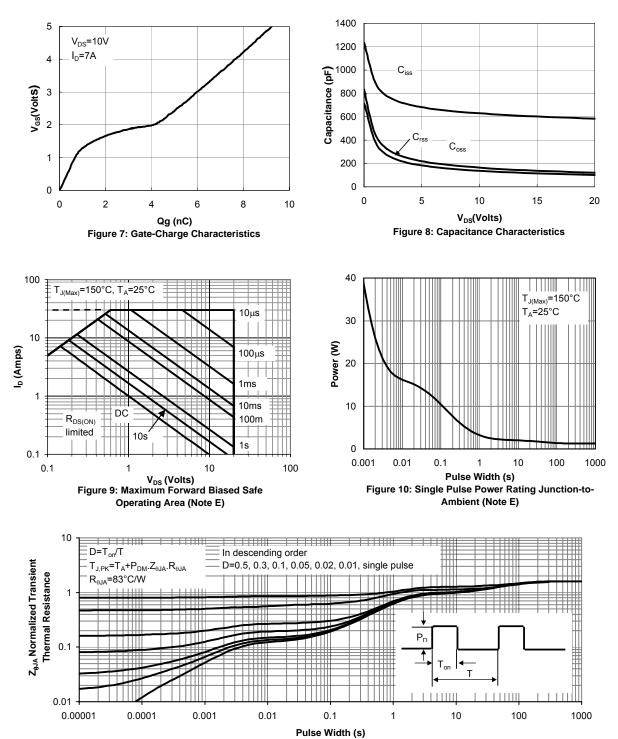


Figure 11: Normalized Maximum Transient Thermal Impedance